



Form PTO-1449 (modified)	U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>		Application Number	10/796,645
		Filing Date	March 9, 2004
		Applicant(s)	Robert Malek, et al.
		Art Unit	2881
		Examiner Name	Anthony G. Quash
SHEET 1	OF 1	Attorney Docket Number	26114.13

U. S. PATENT DOCUMENTS				
Examiner's Initials	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document

FOREIGN PATENT DOCUMENTS					
Examiner's Initials	Cite No.	Foreign Patent Document (Country Code - Number - Kind)	Publication Date MM-DD-YYYY	Patentee or Applicant of Cited Document	Translation Y/N

OTHER DOCUMENTS		
Examiner's Initials	Cite No.	Include name of the author, title of the article, title of the item, date, page(s), volume-issue number(s), publisher, city/country where published
AQ		PCT Search Report (Form PCT/ISA/ 210) issued by the European Patent Office in PCT Application No. PCT/EP2004/002486, 7 pages.
AQ		Senko, Michael W., et al., "External Accumulation of Ions for Enhanced Electrospray Ionization Fourier Transform Ion Cyclotron Resonance Mass Spectrometry", Journal of the American Society for Mass Spectrometry, Vol. 8, pages 970-976, 1997.
AQ		Alford, J.M., et al., "Metal Cluster Ion Cyclotron Resonance: Combining Supersonic Metal Cluster Beam Technology with FT-ICR", International Journal of Mass Spectrometry and Ion Processes, Vol. 72, pages 33-51, 1986.
AQ		Senko, Michael W., et al., "Electrospray Ionization Fourier Transform Ion Cyclotron Resonance at 9.4 T", Rapid Communications in Mass Spectrometry, Vol. 10, pages 1824-1828, 1996.
AQ		Beu, Steven C., "Fourier-Transform Electrospray Instrumentation for Tandem High-Resolution Mass Spectrometry of Large Molecules", Journal of the American Society for Mass Spectrometry, Vol. 4, pages 557-565, 1993.

Examiner Signature	/Anthony Quash/	Date Considered	05/13/2006
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.